



# INTERNATIONAL STANDARD



**Process management for avionics – Atmospheric radiation effects –  
Part 1: Accommodation of atmospheric radiation effects via single event effects  
within avionics electronic equipment**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

### PROCESS MANAGEMENT FOR AVIONICS – ATMOSPHERIC RADIATION EFFECTS –

#### Part 1: Accommodation of atmospheric radiation effects via single event effects within avionics electronic equipment

#### FOREWORD

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IEC 62396-1 has been prepared by IEC technical committee 107: Process management for avionics.

IEC 62396-1 cancels and replaces IEC/TS 62396-1 published in 2006.

This International Standard includes the following technical changes with respect to the Technical Specification:

- a) Guidance has been provided on the environment for altitudes above 60 000 feet (18,3 km) and the effects on electronics are documented in Annex E and F;
- b) Annex G has been added to provide late news as of 2011 on SEE cross-sections applicable to the atmospheric neutron environment.

The text of this international standard is based on the following documents:

FDIS	Report on voting
107/176/FDIS	107/182/RVD

Full information on the voting for the approval of this international standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all the parts in the IEC 62396 series, published under the general title *Process management for avionics – Atmospheric radiation effects*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

**IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.**

## INTRODUCTION

This industry-wide technical specification informs avionics systems designers, electronic equipment, component manufacturers and their customers of the kind of ionising radiation environment that their devices will be subjected to in aircraft, the potential effects this radiation environment can have on those devices, and some general approaches for dealing with these effects.

The same atmospheric radiation (neutrons and protons) that is responsible for the radiation exposure that crew and passengers acquire while flying is also responsible for causing the single event effects (SEE) in the avionics electronic equipment. There has been much work carried out over the last few years related to the radiation exposure of aircraft passengers and crew. A standardised industry approach on the effect of the atmospheric neutrons on electronics should be viewed as consistent with and an extension of the on-going activities related to the radiation exposure of aircraft passengers and crew.

Atmospheric radiation effects are one factor that could contribute to equipment hard and soft fault rates. From a system safety perspective, using derived fault rate values, the existing methodology described in ARP4754 (accommodation of hard and soft fault rates in general) will also accommodate atmospheric radiation effect rates.

In addition, this International Standard refers to the JEDEC Standard JESD89A, which relates to soft errors in electronics by atmospheric radiation at ground level (at altitudes less than 10 000 feet (3 040 m)).

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## PROCESS MANAGEMENT FOR AVIONICS – ATMOSPHERIC RADIATION EFFECTS –

### Part 1: Accommodation of atmospheric radiation effects via single event effects within avionics electronic equipment

#### 1 Scope

This part of IEC 62396 is intended to provide guidance on atmospheric radiation effects on avionics electronics used in aircraft operating at altitudes up to 60 000 feet (18,3 km). It defines the radiation environment, the effects of that environment on electronics and provides design considerations for the accommodation of those effects within avionics systems.

This International Standard is intended to help aerospace equipment manufacturers and designers to standardise their approach to single event effects in avionics by providing guidance, leading to a standard methodology.

Details of the radiation environment are provided together with identification of potential problems caused as a result of the atmospheric radiation received. Appropriate methods are given for quantifying single event effect (SEE) rates in electronic components. The overall system safety methodology should be expanded to accommodate the single event effects rates and to demonstrate the suitability of the electronics for the application at the component and system level.

#### 2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC/TS 62239:2008, *Process management for avionics – Preparation of an electronic components management plan*

NOTE IEC/TS 62239-1, *Process management for avionics – Management plan – Part 1: Preparation and maintenance of an electronic components management plan* is under study and will supersede IEC/TS 62239.

IEC/TS 62396-2:2008, *Process management for avionics – Atmospheric radiation effects – Part 2: Guidelines for single event effects testing for avionics systems*

IEC/TS 62396-3, *Process management for avionics – Atmospheric radiation effects – Part 3: Optimising system design to accommodate the single event effects (SEE) of atmospheric radiation*

IEC/TS 62396-4:2008, *Process management for avionics – Atmospheric radiation effects – Part 4: Guidelines for designing with high voltage aircraft electronics and potential single event effects*

IEC/TS 62396-5, *Process management for avionics – Atmospheric radiation effects – Part 5: Guidelines for assessing thermal neutron fluxes and effects in avionics systems*